

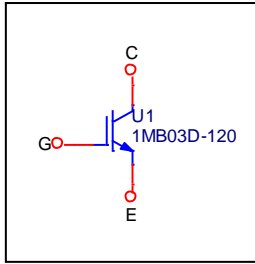
# Device Modeling Report

COMPONENTS: Insulated Gate Bipolar Transistor (IGBT)  
PART NUMBER: 1MB03D-120  
MANUFACTURER: Fuji Electric



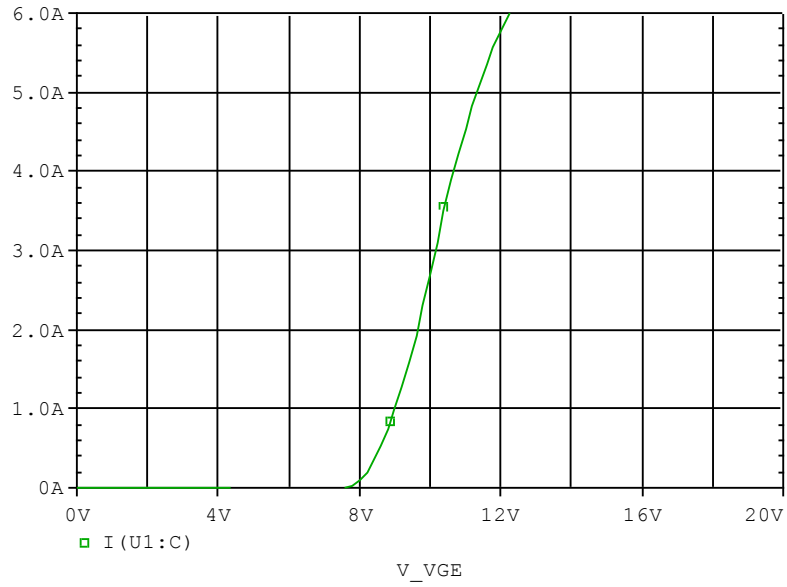
**Bee Technologies Inc.**

## Circuit Configuration

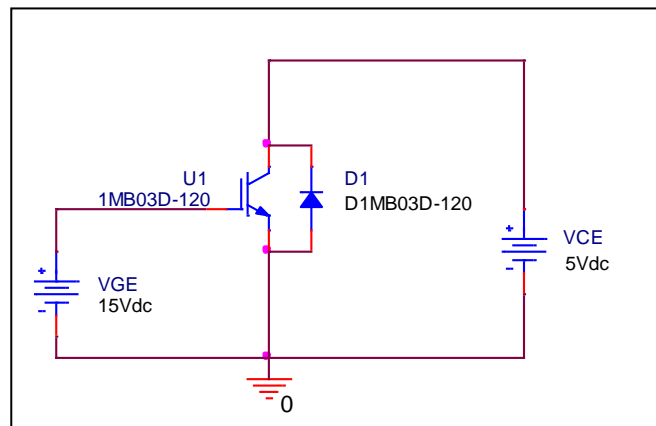


# Transfer Characteristics

## Circuit Simulation result

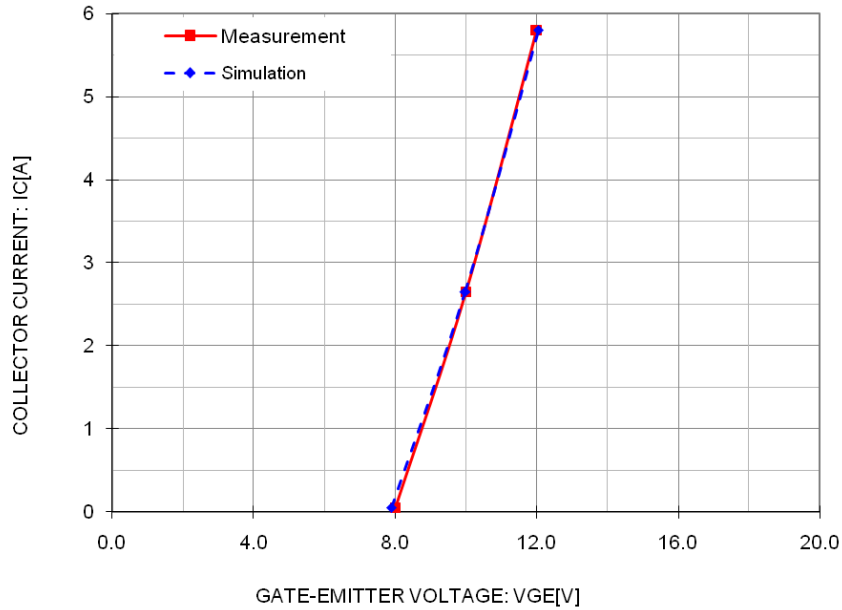


## Evaluation circuit



# Comparison Graph

## Simulation result



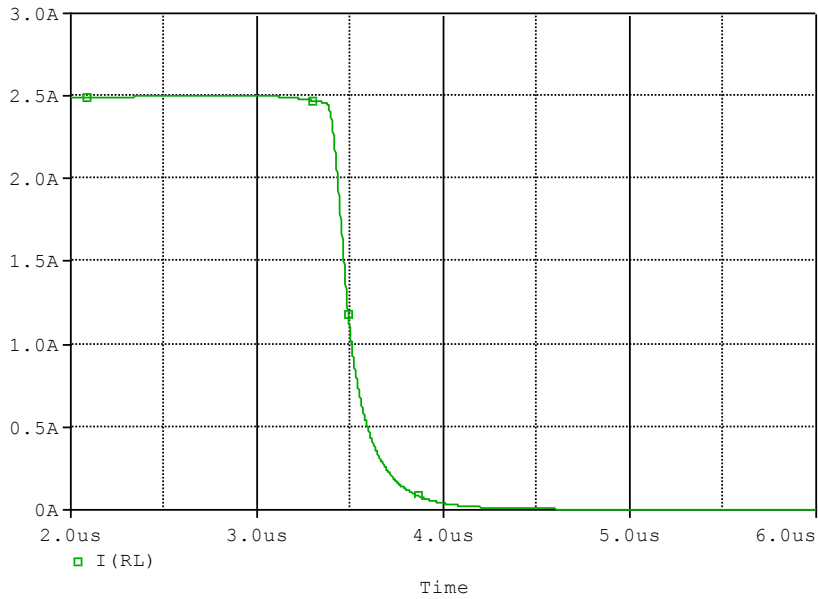
## Comparison table

Test condition:  $V_{CE} = 5$  (V)

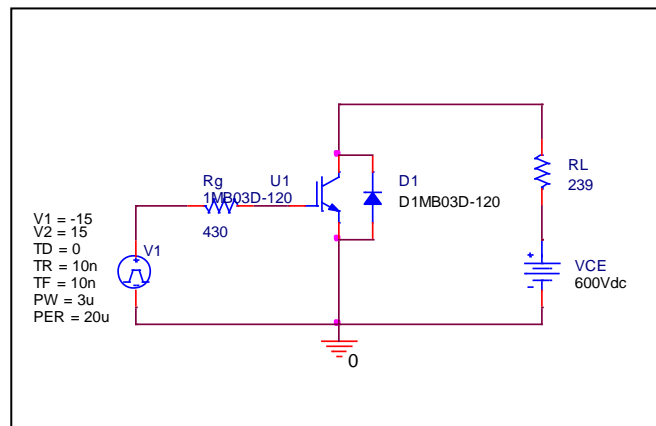
IC (A)	VGE (V)		%Error
	Measurement	Simulation	
0.050	8.000	7.883	-1.46
2.650	10.000	9.981	-0.19
5.800	12.000	12.039	0.32

# Fall Time Characteristics

## Circuit Simulation result



## Evaluation circuit

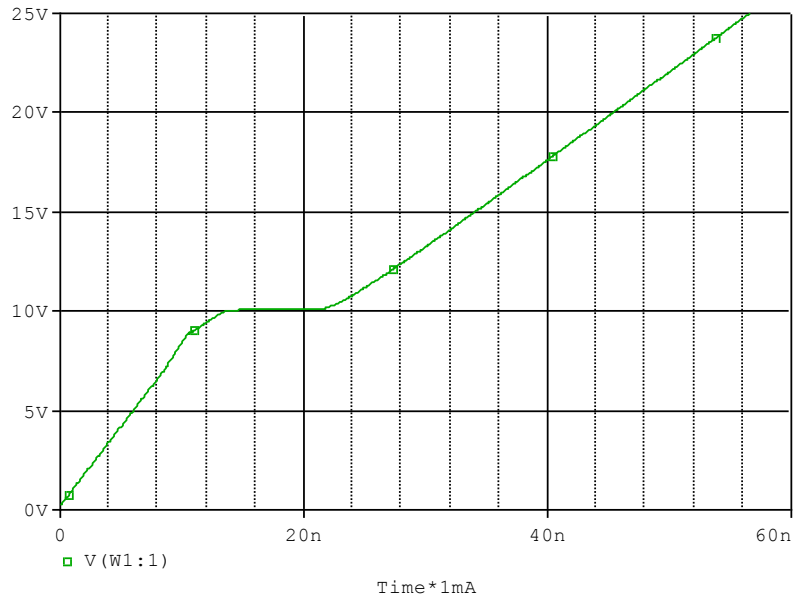


Test condition:  $I_C=2.5$  (A),  $V_{CC}=600$  (V)

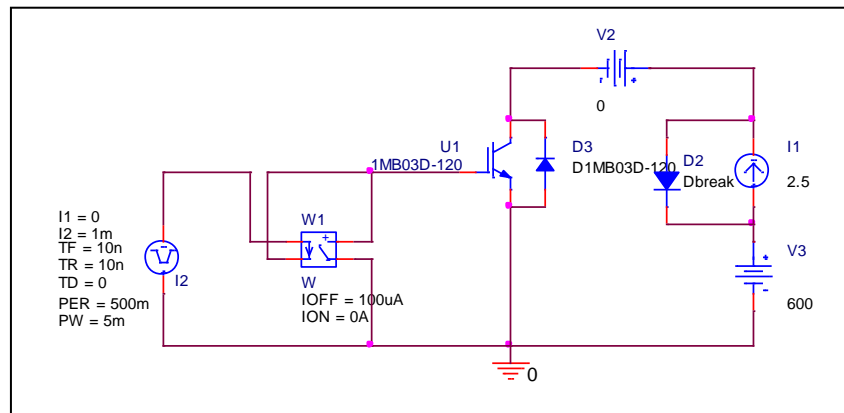
Parameter	Unit	Measurement	Simulation	%Error
tf	us	0.280	0.280	0.157

# Gate Charge Characteristics

## Circuit Simulation result



## Evaluation circuit

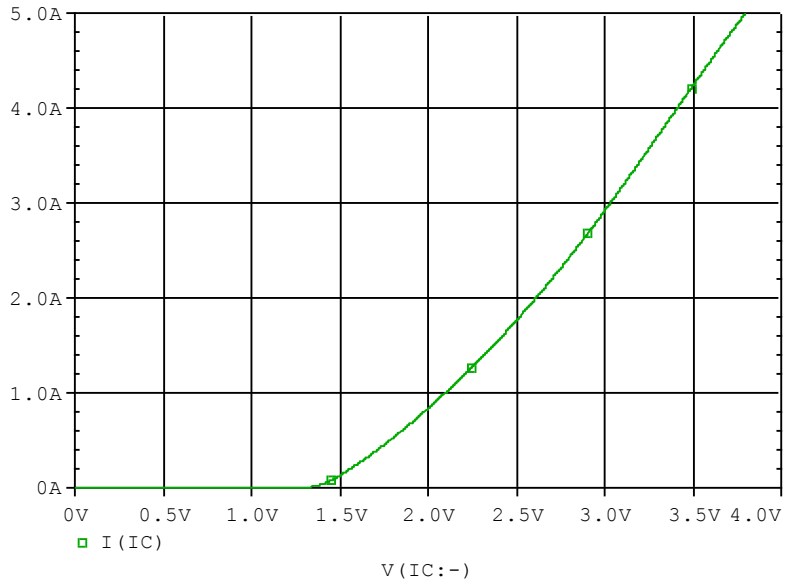


Test condition:  $V_{CC}=600$  (V),  $I_C=2.5$  (A),  $V_{GE}=15$  (V)

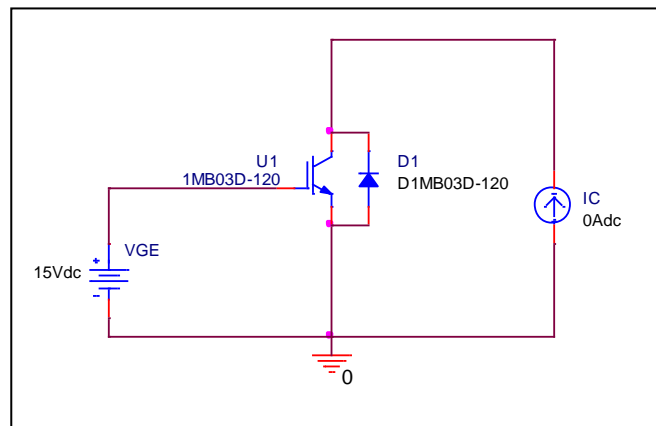
Parameter	Unit	Measurement	Simulation	%Error
<b>Qge</b>	<b>nc</b>	<b>12.000</b>	<b>11.927</b>	<b>-0.608</b>
<b>Qgc</b>	<b>nc</b>	<b>11.000</b>	<b>10.833</b>	<b>-1.518</b>
<b>Qg</b>	<b>nc</b>	<b>33.500</b>	<b>34.034</b>	<b>1.594</b>

# Saturation Characteristics

## Circuit Simulation result

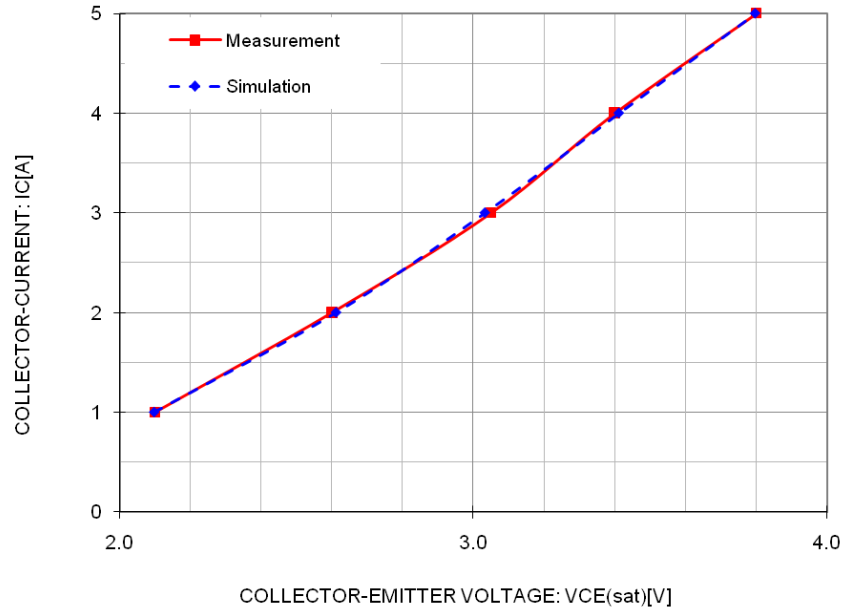


## Evaluation circuit



## Comparison Graph

### Simulation result



### Comparison table

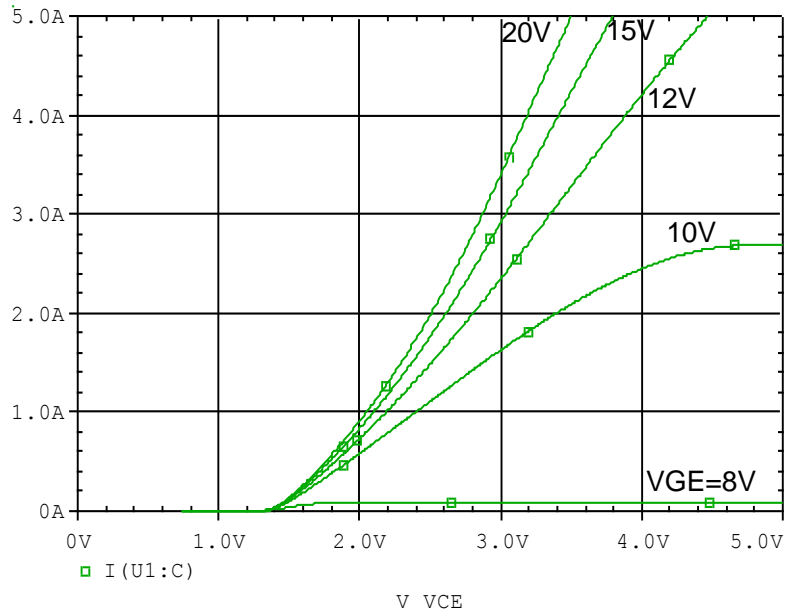
Test condition:  $V_{GE} = 15$  (V)

Ic(A)	VCE (V)		%Error
	Measurement	Simulation	
1.00	2.100	2.098	-0.11
2.00	2.600	2.612	0.46
3.00	3.050	3.033	-0.57
4.00	3.400	3.412	0.34
5.00	3.800	3.797	-0.07

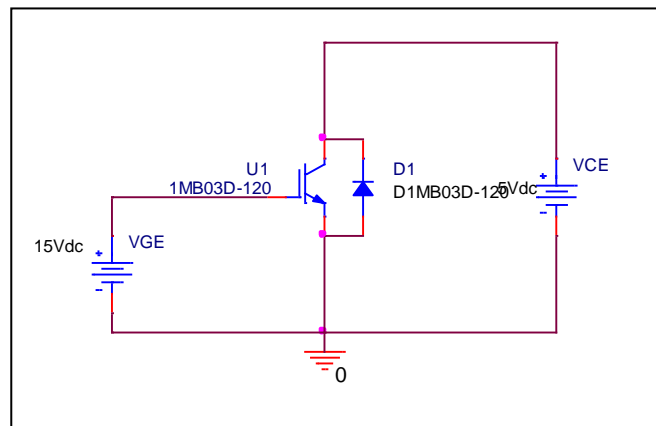


# Output Characteristics

## Circuit Simulation result

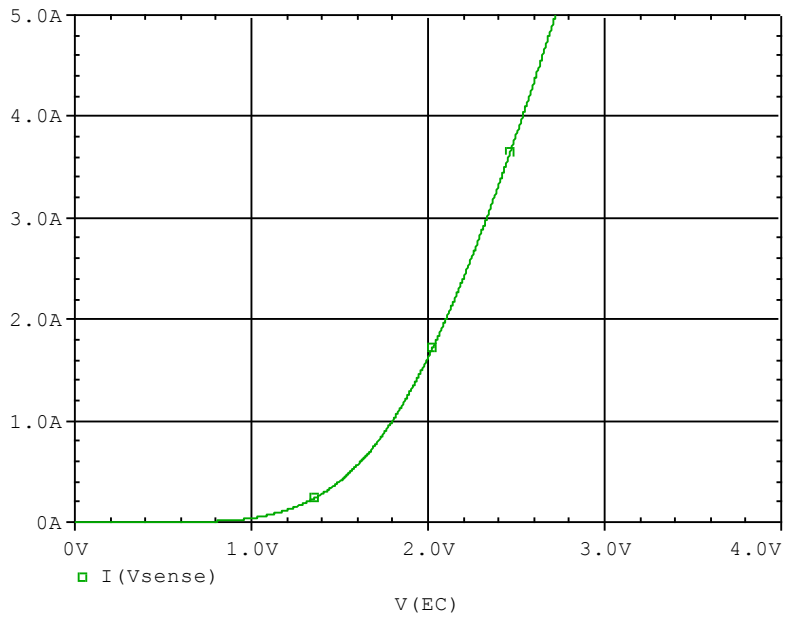


## Evaluation circuit

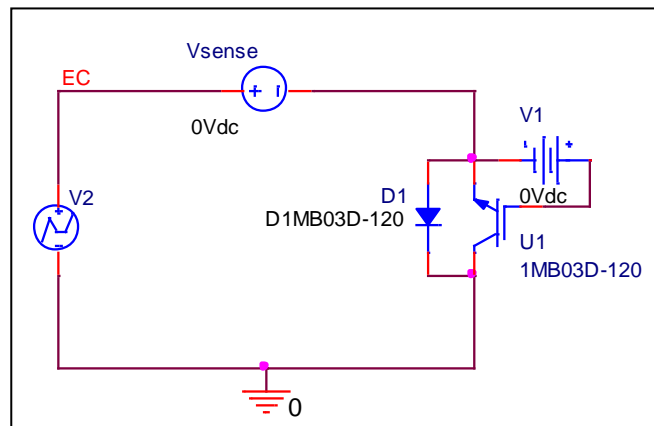


# FWD Forward Current Characteristics

## Circuit Simulation result

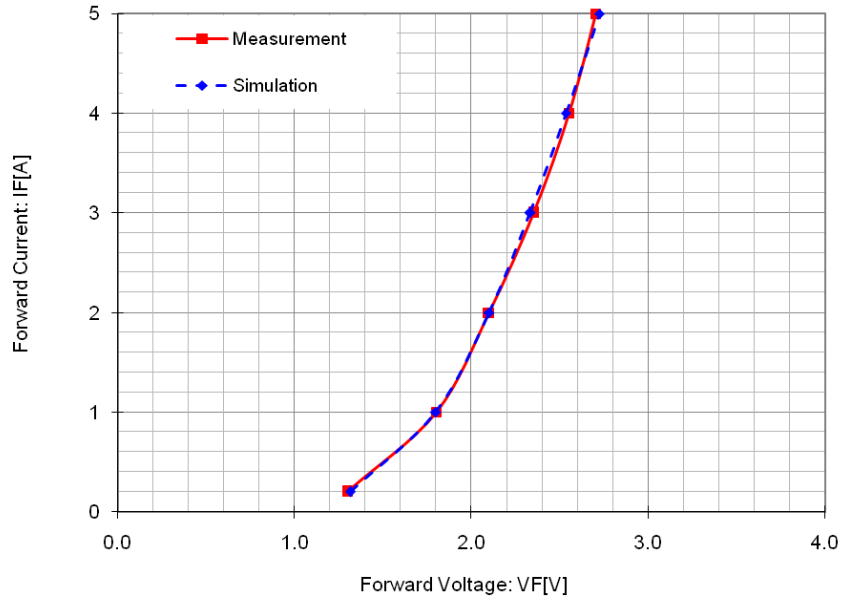


## Evaluation circuit



## Comparison Graph

### Simulation result

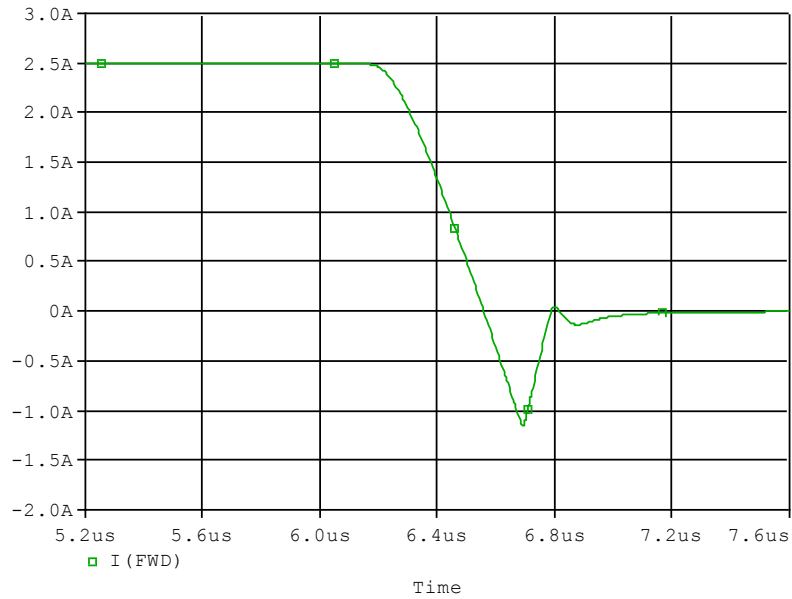


### Comparison table

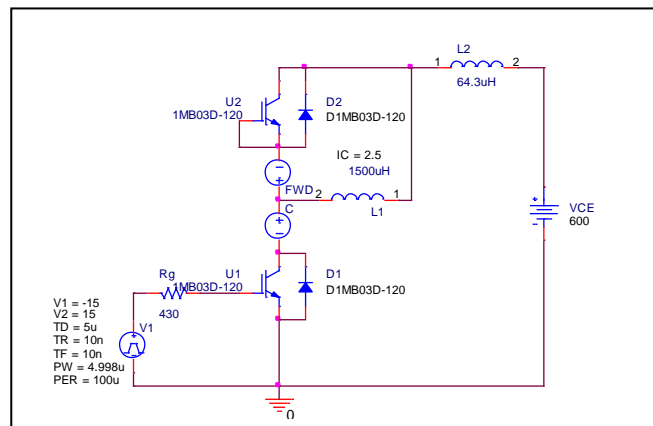
IF(A)	VF (V)		%Error
	Measurement	Simulation	
0.2	1.300	1.315	1.18
1	1.800	1.799	-0.08
2	2.100	2.101	0.04
3	2.350	2.332	-0.75
4	2.550	2.535	-0.58
5	2.700	2.722	0.81

# Reverse Recovery Characteristics

## Circuit Simulation result



## Evaluation circuit



Test condition:  $V_{CC}=600$  (V),  $I_C=2.5$  (A)  $di/dt=-7.5A/usec$

Parameter	Unit	Measurement	Simulation	%Error
trr	nsec	290.000	218.720	-24.58
Irr	A	1.150	1.155	0.44